

L Number	Hits	Search Text	DB	Time stamp
1	187	test near handler and semiconductor adj device	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:35
2	3	test near handler and semiconductor adj device and carrier adj base	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:32
3	6654	Hwang near Hyun Joo.inv.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:33
5	57	Hwang near Hyun .inv.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:33
6	6	Hwang near Hyun .inv. and index near head	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:34
7	0	2002303650.URPN.	USPAT	2004/06/21 11:34
8	34502	test and semiconductor adj device	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:36
9	34502	test and semiconductor adj device elevating near means and head near holder and heating near part	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:36
10	0	test and semiconductor adj device and elevating near means and head near holder and heating near part	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:37
11	64	index near head and 29/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:51
12	1	index near head and 29/\$.ccls. and test near socket	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:57

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Report - 6/21/04*

12	5	head and 29/\$.ccls. and test near socket and semiconductor and holding and carrier near base	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 12:11
13	33	head and 29/\$.ccls. and test near socket and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 12:41
14	14	("3731191" "3906363" "4460236" "4547964" "4554506" "4846702" "4952872" "4978912" "5041183" "5122070" "5286944" "5436570" "5635849" "5642056").PN.	USPAT	2004/06/21 12:19
15	69	test adj head near socket and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 12:56
16	18	("3979671" "4370011" "4604572" "4607220" "4734872" "4739257" "4791364" "4848090" "4962355" "4982153" "5126656" "5166607" "5172049" "5283854" "5360348" "5373893" "5523678" "5528159").PN.	USPAT	2004/06/21 12:51
17	2	test adj head near socket and semiconductor and 29/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:05
19	0	index adj head near test\$3 and semiconductor and 29/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 12:57
20	3	index adj head near test\$3 and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 12:58
18	13749	index adj head near test\$3and semiconductor and 29/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:05
21	0	test adj head near socket and 29/\$.ccls. and peter near vo .xa.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:05

22	0	test adj head and 29/\$.cccls. and peter near vo .xa.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:06
23	79	test adj head and 29/\$.cccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:11
24	23	("3453714" "3623637" "3736651" "4079489" "4149311" "4292116" "4304514" "4375126" "4381601" "4393579" "4437232" "4439917" "4459743" "4476626" "4480780" "4515507" "4527327" "4567652" "4584764" "4586252" "4588092" "4610473" "4670979").PN.	USPAT	2004/06/21 13:14
25	3	index\$3 near head and testing and handling and 29/\$.cccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:12
26	1	index\$3 near head and testing and handling and (219/80; 219/85 ; 219/121EB ; 219/121L ; 219/158 ; 29/593 ; 29/407 ; 29/574).cccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:12
27	1	index\$3 near head and testing and (219/80; 219/85 ; 219/121EB ; 219/121L ; 219/158 ; 29/593 ; 29/407 ; 29/574).cccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:12
28	5	("4205433" "4234418" "4250615" "4314402" "4342090").PN.	USPAT	2004/06/21 13:14
29	0	indexing near head and 29/\$.cccls. and 324/\$.cccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:15
30	23	test near apparatus and head and 29/\$.cccls. and 324/\$.cccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:17
31	241	test near apparatus and head and (324/760; 324/765 ; 324/757 ; 324/762 ; 324/755 ; 324/754; 29/874 ; 29/876 ; 438/14).cccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:18

32	1	test near apparatus and head and (324/760; 324/765 ; 324/757 ; 324/762 ; 324/755 ; 324/754; 29/874 ; 29/876 ; 438/14).ccls. and index and carrier and holder	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:18
33	14	("3826984" "3867698" "4329642" "4382228" "4677474" "4733172" "4841231" "4899099" "4912399" "5006792" "5086269" "5088190" "5148103" "5302891").PN.	USPAT	2004/06/21 13:22
-	2	index adj head near mounting	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:29
-	3	index adj head and mounting near apparatus	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/18 12:32
-	198	index adj head and apparatus	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/18 12:32
-	9	index adj head and apparatus and semiconductor near device	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/18 12:33
-	19	index adj head and semiconductor near device	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/18 12:35
-	13	index adj head and test near handler	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/18 12:35